Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/715,769	INAGAKI ET AL.
	Examiner	Art Unit
	J. Derek Rutten	2192

SEARCHED

Class	Subclass	Date	Examiner
717	128	4/20/2006	JDR
714	45	4/20/2006	JDR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Inventor Name Search EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	4/19/2006	JDR
PLUS database search - see search history printout	4/20/2006	JDR
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	4/20/2006	JDR
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	4/21/2006	JDR
717/128, 714/45 text search only - see search history printout	4/21/2006	JDR
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	4/25/2006	JDR
717 and 714 text search only - see search history printout	4/25/2006	**JDR**
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history	4/26/2006	JDR

Search Notes (continued)	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/715,769	INAGAKI ET AL.
	Examiner	Art Unit
	J. Derek Rutten	2192

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Marc Bookbinder (consulter re. 101)	4/26/2006	JDR
ACM - portal.acm.org IEEE - ieeexplore.ieee.org Google - www.google.com Google scholar - scholar.google.com See srch printout	4/20/2006	JDR
ACM - portal.acm.org See search history printout	4/25/2006	JDR

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner